Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/632,011	SUBIRADA ET AL.	
Examiner	Art Unit	
Hai C. Pham	2861	

	SEARCHED				
Class	Subclass	Date	Examiner		
347	15, 19, 107, 116- 117	7/2/2005	НР		
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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(INCLUDING SI	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
EAST	7/2/2005	НР		